Dimple Vijay Kochar

EDUCATION

Massachusetts Institute of Technology (MIT)

PhD - Electrical Engineering & Computer Science (EECS)

◆ GPA: 5.00 / 5.00

Sep 2021 - Jun 2026

Advisors: Anantha P. Chandrakasan, Prof. Hae-Seung Lee Received the Grass Instrument Company Fellowship 2021-22 Received the MathWorks Engineering Fellowship 2025-26

Indian Institute of Technology Bombay (IITB)

Bachelor & Master of Technology - Electrical Engineering

◆ GPA: 9.34 / 10.00 ☐ Jul 2016 - Aug 2021 Awarded the Sharad Maloo Memorial Gold Medal (1 of 999)

Received the Desai-Sethi Family Scholarship 2016-20

RESEARCH INTERESTS

GenAI for chip design and analog circuits, accelerator design, ML for circuit performance prediction

RESEARCH PROJECTS

LLM-enhanced Analog Circuit Design Optimization

- Proposed using LLMs to reduce the design space for analog circuit sizing, without design annotation or training
- Achieved up to 20% improvement in low-complexity opamps and 55% in high-complexity op-amps over the best baseline, with a speedup of 1.6x on average across nodes
- Benchmarked 22 amplifier topologies across four FinFET technology nodes, among the first to show generalization

Low Power Speech Enhancement Chip for IoT Devices

- Fabricated in TSMC 28nm CMOS process, chip consumes 407 µW or 3.24 µJ/frame with processing time under 8ms
- Achieved the highest audio quality evaluation score (PESQ) of 2.79 across a -6 to 9 dB SNR range on CHiME2

Machine Learning for Circuit Performance Prediction

 Created an ML-driven framework for predicting between schematic and layout simulations, multi-corners, and measured silicon data in commercial 14nm node, and migration to 5nm node with <5% MAPE with <30% data to train

Time To Failure Estimation of SRAM due to RTN

- Proposed estimation of TTF distribution of a stored bit under multi-level RTN using a current injection model
- Demonstrated via MC circuit simulations across supply voltages that process variations worsen TTF distribution

HKMG Process Impact on Gate Leakage, SILC & PBTI

- Extracted bulk trap densities from SILC measurements of differently processed NMOS using WKB tunneling model and modeled with a Reaction-Diffusion-Drift framework
- Modelled the time kinetics of traps generated from PBTI stress using the double interface H/H₂ RD framework

RESEARCH INTERNSHIPS

NVIDIA

PhD Research Intern: ASIC & VLSI Research

Austin, TX, USA

Jun 2025 - Aug 2025

Qualcomm

Making In-Memory Computing Reliable

- ¶ San Diego, CA, USA ☐ Jun 2023 Aug 2023
- Worked on a circuit technique for an accurate and robust against process variations IMC design
- Secondarily, developed a ref. circuit + ML model with 96.4% bit accuracy for IMC in TSMC N3E 8T SRAM

Kavli Institute of Nanoscience, TU Delft

Dipole-Exchange Spin Waves in Ferromagnetic Films

- P Delft, Netherlands
- May 2019 Jun 2019
- Calculated the wave function, magnetization and dipolar field profiles for various spin wave modes; got dispersion relation and chirality variation with thickness

PATENT APPLICATIONS

- D. Kochar, X. Zhang, A. Chandrakasan, "Design Space Reduction and Optimization for Analog Circuits," U.S. App. No. 19/247,091, 2025.

 MIT, IBM
- S. Kim, C. Jung, **D. Kochar**, "Compute-in-Memory with Current Transition Detection," U.S. App. No. 18/403,010, 2024. *Qualcomm*

SELECTED PUBLICATIONS

- D. Kochar et al., "LEDRO: LLM-Enhanced Design Space Reduction and Optimization for Analog Circuits,", IEEE International Conference on LLM-Aided Design (ICLAD) 2025, best paper candidate; WIP poster at Design Automation Conference (DAC), 2025.
- D. Kochar et al., "Efficient Circuit Performance Prediction Using Machine Learning: From Schematic to Layout and Silicon Measurement with Minimal Data Input," Int. Symposium on Circuits and Systems 2025, awarded best track manuscript; extended manuscript accepted at IEEE Transactions on Circuits And Systems-I (TCAS-I).
 MIT, MIT-IBM Watson AI Lab
- D. Kochar et al., "A 0.75mm² 407μW real-time speech audio denoiser with quantized cascaded redundant convolutional encoder-decoder for wearable IoT devices," Int. Conference on VLSI Design 2025.
- D. Kochar et al., "Estimation of Time to Failure Distribution in SRAM Due to Trapped Oxide Charges," IEEE
 Int. Symp. on Circuits and Systems 2021.
- **D. Kochar** et *al.*, "Modeling of HKMG Stack Process Impact on Gate Leakage, SILC and PBTI," *IEEE International Reliability Physics Symposium (IRPS)* 2021. **IITB**